

## SILICON LIFE TIME MEASUREMENT SYSTEM

### HR-90R



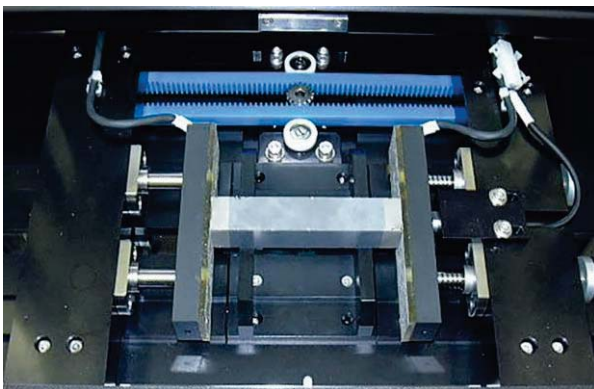
- Single Point, Non-Contact using photoconduction vibration decay method
- Software data processing using Digital Oscilloscope
- Measure Range: 100uS to 5000uS
- Sample Size: On Request

### APPLICABLE MATERIALS

- Silicon ingot, Silicon bulk, Prismatic shape (JIS code)

### HF-100DCA

- Single Point, Contact Type using JIS direct current anodizing method
- Global standard model for the lifetime test of silicon bulk
- Software data processing using Digital Oscilloscope
- Measure Range: 50uS to 20mS
- Sample Size: On Request



### APPLICABLE MATERIALS

- Silicon ingot, Silicon bulk, Prismatic shape (JIS code)